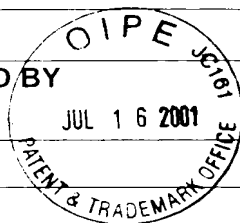


U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)		Docket No. APPM/4969	Serial No. 09/785,815
<b>LISTS OF PATENTS AND PUBLICATIONS CITED BY APPLICANT</b>		Applicant MOK, et al.	
(Use several sheets if necessary)		Filing Date February 16, 2001	Group Unknown
Examiner Unknown			

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*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
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<i>ju</i>	A2	6,093,291	07/25/2000	Izumi, et al.	204	224 R	07/31/1998
<i>ju</i>	A3	6,071,388	06/06/2000	Uzoh	204	297 R	05/29/1998
<i>ju</i>	A4	6,024,856	02/15/2000	Haydu, et al.	205	84	10/10/1997
<i>ju</i>	A5	5,838,121	11/17/1998	Fairbairn, et al.	318	45	11/18/1996
<i>ju</i>	A6	5,730,890	03/24/1998	Bickford, et al.	216	87	09/12/1996
<i>ju</i>	A7	5,723,028	03/03/1998	Poris	204	231	10/19/1994
<i>ju</i>	A8	5,718,813	02/17/1998	Drummond, et al.	204	192.12	04/02/1993
<i>ju</i>	A9	5,705,223	01/06/1998	Bunkofske	427	240	12/05/1995
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<i>ju</i>	A11	5,625,170	04/29/1997	Poris	177	50	01/18/1994
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<i>ju</i>	A14	5,516,412	05/14/1996	Andricacos, et al.	204	224 R	05/16/1995

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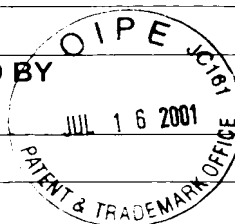
*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
							YES	NO
<i>ju</i>	B1	97/12079	04/03/1997	WO	C25D	5/02	X	
<i>ju</i>	B2	99/25902	05/27/1999	WO	C25B	13/00	X	
<i>ju</i>	B3	99/25903	05/27/1999	WO	C25D	5/00	X	
<i>ju</i>	B4	99/25904	05/27/1999	WO	C25D	5/02	X	
<i>ju</i>	B5	99/25905	05/25/1999	WO	C25D	5/02	X	

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<i>ju</i>	C1	"Wafer Back Surface Film Removal", Colombo, L., Central R&D, SGS-THOMSON Microelectronics, Agrate, Italy, 6 pages.
<i>ju</i>	C2	"Metallization & Interconnect", SEMITool Products Sales, October 27, 1998, 4 pages.
Examiner	<i>W. J. ...</i>	
	Date Considered	<i>2/20/03</i>

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)		Docket No. APPM/4969	Serial No. 09/785,815
<b>LISTS OF PATENTS AND PUBLICATIONS CITED BY APPLICANT</b>		Applicant MOK, et al.	
(Use several sheets if necessary)		Filing Date February 16, 2001	Group Unknown
Examiner Unknown			

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	A15	5,454,930	10/03/1995	Miura, et al.	205	159	07/28/1994
	A16	5,447,615	09/05/1995	Ishida	204	224 R	06/22/1994
	A17	5,429,733	07/04/1995	Ishida	204	224 R	05/04/1993
	A18	5,415,890	05/16/1996	Kloiber, et al.	427	242	01/03/1994
	A19	5,377,708	01/03/1995	Bergman, et al.	134	105	04/26/1993
	A20	5,368,711	11/29/1994	Poris	204	193	04/29/1993
	A21	5,349,978	09/27/1994	Sago, et al.	134	153	06/04/1993
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	A23	5,316,974	05/31/1994	Crank	437	190	04/30/1990
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	A25	5,259,407	11/09/1993	Tuchida, et al.	134	151	06/14/1991
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	A27	5,252,807	10/12/1993	Chizinsky	219	390	10/23/1991

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							YES	NO
	B6	99/26275	05/27/1999	WO	H01L		X	
	B7	63-18093 (Abst.)	05/23/1988	JP	C25D	5/18	X	
	B8	58-82823 (Abst.)	10/25/1983	JP	H01L	21/288	X	
	B9	06-17291 (Abst.)	01/25/1994	JP	C25D	7/12	X	
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	C4	"VERTEQ" VERTEQ Online, 5 pages.

Examiner *[Signature]* Date Considered *2/24/01*

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U.S. Department of Commerce, Patent and Trademark Office. (PTO Form 1449 modified)		Docket No. APPM/4969	Serial No. 09/785,815
<b>LISTS OF PATENTS AND PUBLICATIONS CITED BY APPLICANT</b>		Applicant MOK, et al.	
(Use several sheets if necessary)		Filing Date February 16, 2001	Group Unknown
Examiner Unknown			

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<i>hm</i>	A28	5,230,743	07/27/1993	Thompson, et al.	134	32	07/30/1992
<i>hm</i>	A29	5,224,504	07/06/1993	Thompson, et al.	134	155	07/30/1992
<i>hm</i>	A30	5,222,310	06/29/1993	Thompson, et al.	34	202	01/11/1991
<i>hm</i>	A31	5,162,260	11/10/1992	Leibovitz, et al.	437	195	01/07/1991
<i>hm</i>	A32	5,155,336	10/13/1992	Gronet, et al.	219	411	10/24/1991
<i>hm</i>	A33	5,092,975	03/03/1992	Yamamura, et al.	204	198	06/15/1989
<i>hm</i>	A34	5,055,425	10/08/1991	Leibovitz, et al.	437	195	06/01/1989
<i>hm</i>	A35	5,039,381	08/13/1991	Mullarkey	204	47.5	05/25/1989
<i>hm</i>	A36	4,789,445	12/06/1988	Goffman, et al.	204	114	11/19/1986
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							YES	NO
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<i>hm</i>	B12	443 108 A (Abst.)	12/15/1974	SU	C23B	5/20	X	
<i>hm</i>	B13	932 709 (Abst.)	03/17/1955	DE			X	

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<i>hm</i>	C5	"Tantalum, Copper and Damascene: The Future of Interconnects", Singer, P., SEMICONDUCTOR INTERNATIONAL, June 1998, 6 pages.
<i>hm</i>	C6	"Wafer Processing", Singer, P., SEMICONDUCTOR INTERNATIONAL, June 1998, page 70.

Examiner <i>Greg Moch</i>	Date Considered <i>2/20/01</i>
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.	

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am	A41	4,510,176	04/09/1985	Cuthbert, et al.	427	82	09/26/1983
hcn	A42	4,489,740	12/25/1984	Rattan, et al.	134	140	12/27/1982
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hcn	A50	4,113,492	09/12/1978	Sato, et al.	96	67	04/04/1977
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hcn	A52	4,092,176	05/30/1978	Kozai, et al.	134	186	12/07/1976
hcn	A53	4,027,686	06/07/1977	Shortes, et al.	134	95	01/02/1973

*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
							YES	NO
1	B14							
	B15							
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<i>SM</i>	C7	"NEY CONTACT MANUAL", Pitney, K., ELECTRICAL CONTACTS FOR LOW ENERGY USES, October 8, 1974, 19 pages.
<i>SM</i>	C8	"Electric Contacts Theory and Application", Holm, R., Springer-Verlag New York Inc, 1967, 27 pages.

Examiner <u>Gregory W. Hester</u>	Date Considered <u>2/24/05</u>
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

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Docket No.

Serial No.

APPM/4969

09/785,815

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February 16, 2001

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<i>SW</i>	A54	3,770,598	11/06/1973	Creutz	204	52R	01/21/1972
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<i>SW</i>	A56	3,649,509	03/14/1972	Morawetz, et al.	204	238	07/08/1969
<i>SW</i>	A57	2,882,209	04/14/1959	Brown, et al.	204	52	05/20/1957
<i>SW</i>	A58	2,742,413	04/17/1956	Cransberg, et al.	204	52	04/13/1953
<i>SW</i>	A59	09/295,678		Landau			04/21/1999
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<i>SW</i>	A63	09/484,616		Landau, et al.			01/18/2000
<i>SW</i>	A64	09/658,336		Hey, et al.			09/08/2000
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*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
							YES	NO
<i>I</i>	B17							
<i>I</i>	B18							
<i>I</i>	B19							

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<i>I</i>	C09	
<i>I</i>	C10	

Examiner

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Docket No.

Serial No.

(PTO Form 1449 modified)

JUL 16 2001 APPM/4969

09/785,815

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February 16, 2001

Unknown

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<i>lu</i>	A67	09/676,362		Olgado, et al.			09/29/2000
<i>lu</i>	A68	09/678,947		Dordi, et al.			10/03/2000
<i>lu</i>	A69	09/687,053		Hey, et al.			10/12/2000
<i>lu</i>	A70	09/684,500		Olgado			10/06/2000
<i>lu</i>	A71	09/731,326		Dordi, et al.			12/05/2000
<i>lu</i>	A72	09/766,060		Hey, et al.			01/18/2001
	A73						
	A74						
	A75						
	A76						
	A77						
	A78						
	A79						

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<i>1</i>	B20							
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	B23							
	B24							

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	C11	
	C12	

Examiner

*Angela Hock*

Date Considered

*2/7/03*

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